

Welcome to E-XFL.COM

Understanding [Embedded - Microprocessors](#)

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of [Embedded - Microprocessors](#)

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details

Product Status	Active
Core Processor	-
Number of Cores/Bus Width	-
Speed	-
Co-Processors/DSP	-
RAM Controllers	-
Graphics Acceleration	-
Display & Interface Controllers	-
Ethernet	-
SATA	-
USB	-
Voltage - I/O	-
Operating Temperature	-
Security Features	-
Package / Case	-
Supplier Device Package	-
Purchase URL	https://www.e-xfl.com/pro/item?MUrl=&PartUrl=mpc870zt80

7.2 Estimation with Junction-to-Case Thermal Resistance

Historically, thermal resistance has frequently been expressed as the sum of a junction-to-case thermal resistance and a case-to-ambient thermal resistance:

$$R_{\theta JA} = R_{\theta JC} + R_{\theta CA}$$

where:

$R_{\theta JA}$ = junction-to-ambient thermal resistance ($^{\circ}\text{C}/\text{W}$)

$R_{\theta JC}$ = junction-to-case thermal resistance ($^{\circ}\text{C}/\text{W}$)

$R_{\theta CA}$ = case-to-ambient thermal resistance ($^{\circ}\text{C}/\text{W}$)

$R_{\theta JC}$ is device-related and cannot be influenced by the user. The user adjusts the thermal environment to affect the case-to-ambient thermal resistance, $R_{\theta CA}$. For instance, the user can change the airflow around the device, add a heat sink, change the mounting arrangement on the printed-circuit board, or change the thermal dissipation on the printed-circuit board surrounding the device. This thermal model is most useful for ceramic packages with heat sinks where some 90% of the heat flows through the case and the heat sink to the ambient environment. For most packages, a better model is required.

7.3 Estimation with Junction-to-Board Thermal Resistance

A simple package thermal model that has demonstrated reasonable accuracy (about 20%) is a two-resistor model consisting of a junction-to-board and a junction-to-case thermal resistance. The junction-to-case thermal resistance covers the situation where a heat sink is used or where a substantial amount of heat is dissipated from the top of the package. The junction-to-board thermal resistance describes the thermal performance when most of the heat is conducted to the printed-circuit board. It has been observed that the thermal performance of most plastic packages and especially PBGA packages is strongly dependent on the board temperature. If the board temperature is known, an estimate of the junction temperature in the environment can be made using the following equation:

$$T_J = T_B + (R_{\theta JB} \times P_D)$$

where:

$R_{\theta JB}$ = junction-to-board thermal resistance ($^{\circ}\text{C}/\text{W}$)

T_B = board temperature ($^{\circ}\text{C}$)

P_D = power dissipation in package

If the board temperature is known and the heat loss from the package case to the air can be ignored, acceptable predictions of junction temperature can be made. For this method to work, the board and board mounting must be similar to the test board used to determine the junction-to-board thermal resistance, namely a 2s2p (board with a power and a ground plane) and vias attaching the thermal balls to the ground plane.

7.4 Estimation Using Simulation

When the board temperature is not known, a thermal simulation of the application is needed. The simple two-resistor model can be used with the thermal simulation of the application [2], or a more accurate and complex model of the package can be used in the thermal simulation.

7.5 Experimental Determination

To determine the junction temperature of the device in the application after prototypes are available, the thermal characterization parameter (Ψ_{JT}) can be used to determine the junction temperature with a measurement of the temperature at the top center of the package case using the following equation:

$$T_J = T_T + (\Psi_{JT} \times P_D)$$

where:

Ψ_{JT} = thermal characterization parameter

T_T = thermocouple temperature on top of package

P_D = power dissipation in package

The thermal characterization parameter is measured per the JESD51-2 specification published by JEDEC using a 40 gauge type T thermocouple epoxied to the top center of the package case. The thermocouple should be positioned so that the thermocouple junction rests on the package. A small amount of epoxy is placed over the thermocouple junction and over about 1 mm of wire extending from the junction. The thermocouple wire is placed flat against the package case to avoid measurement errors caused by the cooling effects of the thermocouple wire.

7.6 References

Semiconductor Equipment and Materials International (415) 964-5111
 805 East Middlefield Rd
 Mountain View, CA 94043

MIL-SPEC and EIA/JESD (JEDEC) specifications 800-854-7179 or
 (Available from Global Engineering Documents) 303-397-7956

JEDEC Specifications <http://www.jedec.org>

1. C.E. Triplett and B. Joiner, "An Experimental Characterization of a 272 PBGA Within an Automotive Engine Controller Module," Proceedings of SemiTherm, San Diego, 1998, pp. 47–54.
2. B. Joiner and V. Adams, "Measurement and Simulation of Junction to Board Thermal Resistance and Its Application in Thermal Modeling," Proceedings of SemiTherm, San Diego, 1999, pp. 212–220.

8 Power Supply and Power Sequencing

This section provides design considerations for the MPC875/MPC870 power supply. The MPC875/MPC870 has a core voltage (V_{DDL}) and PLL voltage (V_{DDSYN}), which both operate at a lower voltage than the I/O voltage (V_{DDH}). The I/O section of the MPC875/MPC870 is supplied with 3.3 V across V_{DDH} and V_{SS} (GND).

The signals $\overline{PA[0:3]}$, $PA[8:11]$, $PB15$, $PB[24:25]$, $PB[28:31]$, $PC[4:7]$, $PC[12:13]$, $PC15$, $PD[3:15]$, TDI , TDO , TCK , \overline{TRST} , TMS , MII_TXEN , and MII_MDIO are 5 V tolerant. No input can be more than 2.5 V greater than V_{DDH} . In addition, 5-V tolerant pins cannot exceed 5.5 V, and remaining input pins cannot exceed 3.465 V. This restriction applies to power up, power down, and normal operation.

One consequence of multiple power supplies is that when power is initially applied, the voltage rails ramp up at different rates. The rates depend on the nature of the power supply, the type of load on each power supply, and the manner in which different voltages are derived. The following restrictions apply:

- V_{DDL} must not exceed V_{DDH} during power up and power down
- V_{DDL} must not exceed 1.9 V, and V_{DDH} must not exceed 3.465 V

These cautions are necessary for the long-term reliability of the part. If they are violated, the electrostatic discharge (ESD) protection diodes are forward-biased, and excessive current can flow through these diodes. If the system power supply design does not control the voltage sequencing, the circuit shown in Figure 4 can be added to meet these requirements. The MUR420 Schottky diodes control the maximum potential difference between the external bus and core power supplies on power up, and the 1N5820 diodes regulate the maximum potential difference on power down.

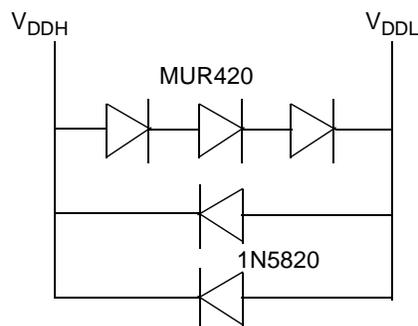


Figure 4. Example Voltage Sequencing Circuit

9 Mandatory Reset Configurations

The MPC875/MPC870 requires a mandatory configuration during reset.

If hardware reset configuration word (HRCW) is enabled, the HRCW[DBGC] value needs to be set to binary X1 in the HRCW and the SIUMCR[DBGC] should be programmed with the same value in the boot code after reset. This can be done by asserting the $\overline{\text{RSTCONF}}$ during $\overline{\text{HRESET}}$ assertion.

If HRCW is disabled, the SIUMCR[DBGC] should be programmed with binary X1 in the boot code after reset by negating the $\overline{\text{RSTCONF}}$ during the $\overline{\text{HRESET}}$ assertion.

The MBMR[GPLB4DIS], PAPAN, PADIR, PBPAN, PBDIR, PCPAN, and PCDIR need to be configured with the mandatory values in Table 7 in the boot code after the reset is negated.

Table 7. Mandatory Reset Configuration of MPC875/MPC870

Register/Configuration	Field	Value (Binary)
HRCW (Hardware reset configuration word)	HRCW[DBGC]	X1
SIUMCR (SIU module configuration register)	SIUMCR[DBGC]	X1
MBMR (Machine B mode register)	MBMR[GPLB4DIS]	0
PAPAN (Port A pin assignment register)	PAPAN[5:9] PAPAN[12:13]	0

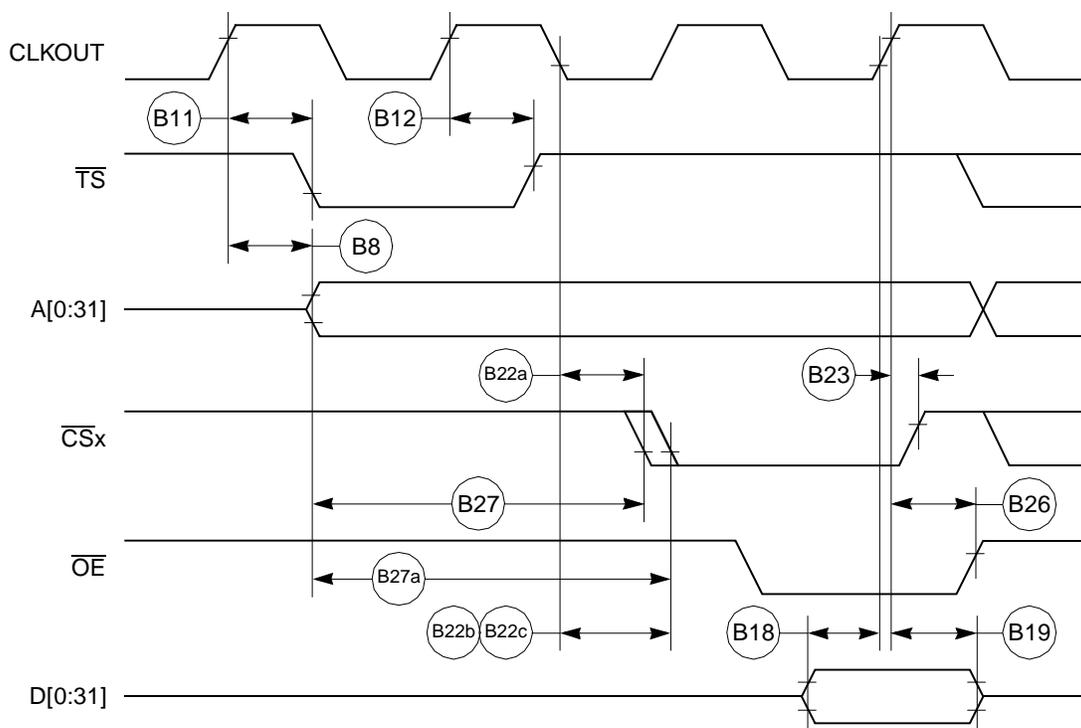


Figure 15. External Bus Read Timing (GPCM Controlled—TRLX = 1, ACS = 10, ACS = 11)

Figure 16 through Figure 18 provide the timing for the external bus write controlled by various GPCM factors.

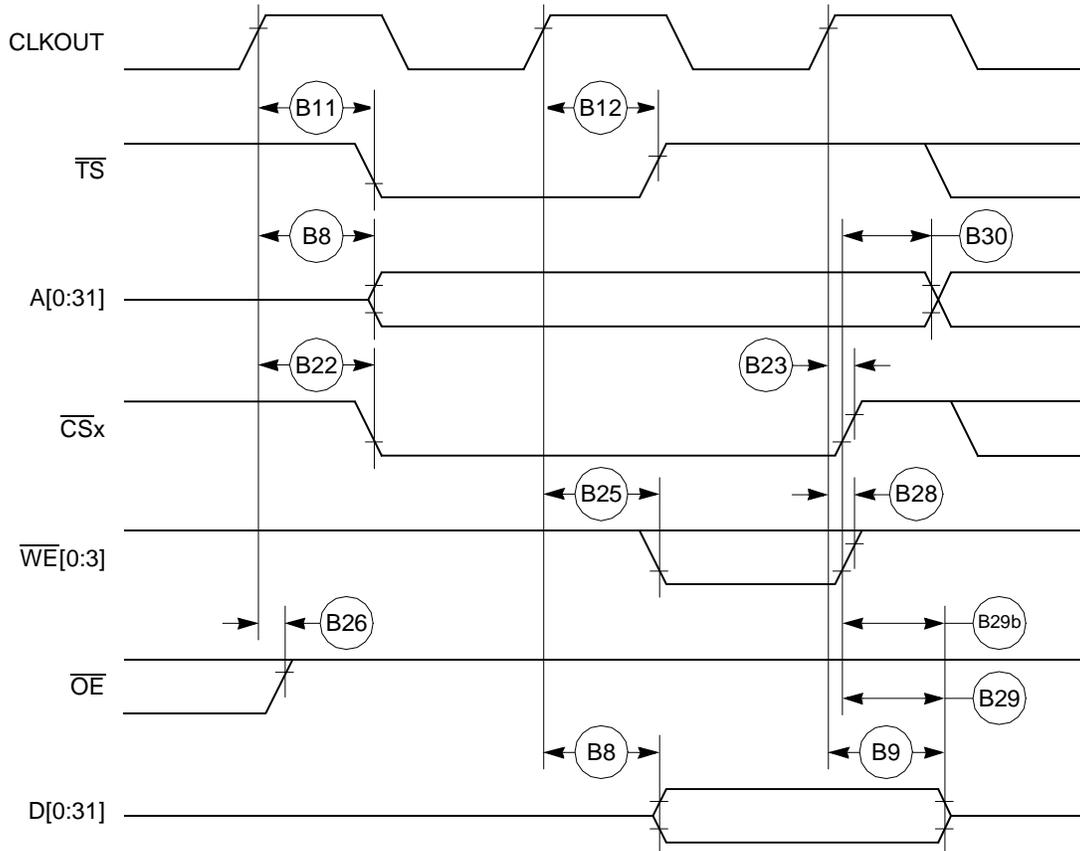


Figure 16. External Bus Write Timing (GPCM Controlled—TRLX = 0, CSNT = 0)

Table 11 provides the interrupt timing for the MPC875/MPC870.

Table 11. Interrupt Timing

Num	Characteristic ¹	All Frequencies		Unit
		Min	Max	
I39	$\overline{\text{IRQ}}_x$ valid to CLKOUT rising edge (setup time)	6.00		ns
I40	$\overline{\text{IRQ}}_x$ hold time after CLKOUT	2.00		ns
I41	$\overline{\text{IRQ}}_x$ pulse width low	3.00		ns
I42	$\overline{\text{IRQ}}_x$ pulse width high	3.00		ns
I43	$\overline{\text{IRQ}}_x$ edge-to-edge time	$4 \times T_{\text{CLKOUT}}$		—

¹ The I39 and I40 timings describe the testing conditions under which the $\overline{\text{IRQ}}_x$ lines are tested when being defined as level sensitive. The $\overline{\text{IRQ}}_x$ lines are synchronized internally and do not have to be asserted or negated with reference to the CLKOUT. The I41, I42, and I43 timings are specified to allow correct functioning of the $\overline{\text{IRQ}}_x$ lines detection circuitry and have no direct relation with the total system interrupt latency that the MPC875/MPC870 is able to support.

Figure 25 provides the interrupt detection timing for the external level-sensitive lines.

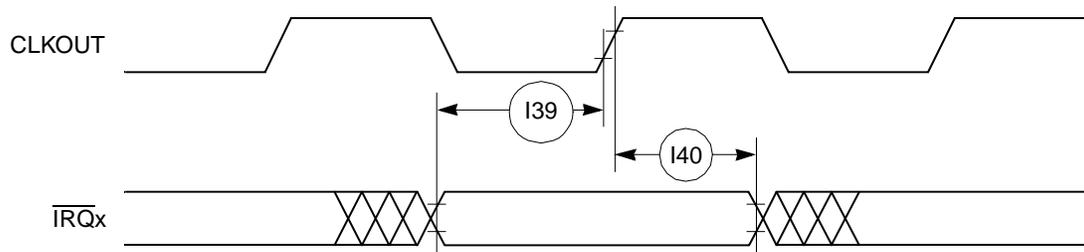


Figure 25. Interrupt Detection Timing for External Level Sensitive Lines

Figure 26 provides the interrupt detection timing for the external edge-sensitive lines.

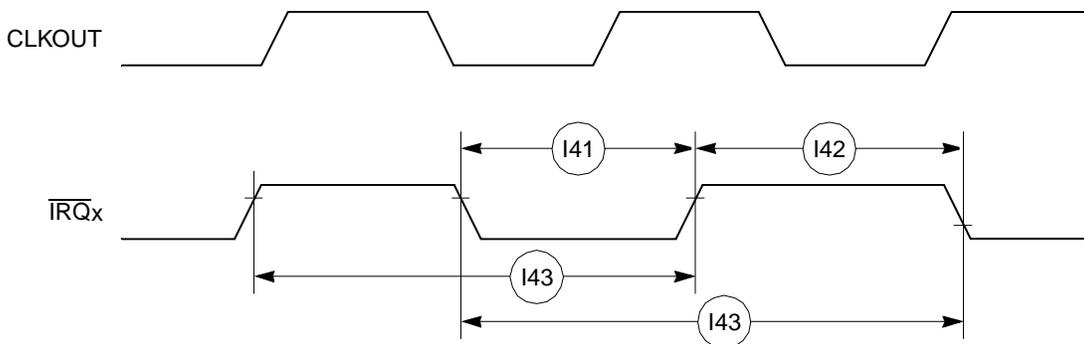


Figure 26. Interrupt Detection Timing for External Edge-Sensitive Lines

Table 12 shows the PCMCIA timing for the MPC875/MPC870.

Table 12. PCMCIA Timing

Num	Characteristic	33 MHz		40 MHz		66 MHz		80 MHz		Unit
		Min	Max	Min	Max	Min	Max	Min	Max	
P44	A(0:31), $\overline{\text{REG}}$ valid to PCMCIA strobe asserted ¹ (MIN = $0.75 \times B1 - 2.00$)	20.70	—	16.70	—	9.40	—	7.40	—	ns
P45	A(0:31), $\overline{\text{REG}}$ valid to ALE negation ¹ (MIN = $1.00 \times B1 - 2.00$)	28.30	—	23.00	—	13.20	—	10.50	—	ns
P46	CLKOUT to $\overline{\text{REG}}$ valid (MAX = $0.25 \times B1 + 8.00$)	7.60	15.60	6.30	14.30	3.80	11.80	3.13	11.13	ns
P47	CLKOUT to $\overline{\text{REG}}$ invalid (MIN = $0.25 \times B1 + 1.00$)	8.60	—	7.30	—	4.80	—	4.125	—	ns
P48	CLKOUT to $\overline{\text{CE1}}$, $\overline{\text{CE2}}$ asserted (MAX = $0.25 \times B1 + 8.00$)	7.60	15.60	6.30	14.30	3.80	11.80	3.13	11.13	ns
P49	CLKOUT to $\overline{\text{CE1}}$, $\overline{\text{CE2}}$ negated (MAX = $0.25 \times B1 + 8.00$)	7.60	15.60	6.30	14.30	3.80	11.80	3.13	11.13	ns
P50	CLKOUT to $\overline{\text{PCOE}}$, $\overline{\text{IORD}}$, $\overline{\text{PCWE}}$, $\overline{\text{IOWR}}$ assert time (MAX = $0.00 \times B1 + 11.00$)	—	11.00	—	11.00	—	11.00	—	11.00	ns
P51	CLKOUT to $\overline{\text{PCOE}}$, $\overline{\text{IORD}}$, $\overline{\text{PCWE}}$, $\overline{\text{IOWR}}$ negate time (MAX = $0.00 \times B1 + 11.00$)	2.00	11.00	2.00	11.00	2.00	11.00	2.00	11.00	ns
P52	CLKOUT to ALE assert time (MAX = $0.25 \times B1 + 6.30$)	7.60	13.80	6.30	12.50	3.80	10.00	3.13	9.40	ns
P53	CLKOUT to ALE negate time (MAX = $0.25 \times B1 + 8.00$)	—	15.60	—	14.30	—	11.80	—	11.13	ns
P54	$\overline{\text{PCWE}}$, $\overline{\text{IOWR}}$ negated to D(0:31) invalid ¹ (MIN = $0.25 \times B1 - 2.00$)	5.60	—	4.30	—	1.80	—	1.125	—	ns
P55	$\overline{\text{WAITA}}$ and $\overline{\text{WAITB}}$ valid to CLKOUT rising edge ¹ (MIN = $0.00 \times B1 + 8.00$)	8.00	—	8.00	—	8.00	—	8.00	—	ns
P56	CLKOUT rising edge to $\overline{\text{WAITA}}$ and $\overline{\text{WAITB}}$ invalid ¹ (MIN = $0.00 \times B1 + 2.00$)	2.00	—	2.00	—	2.00	—	2.00	—	ns

¹ PSST = 1. Otherwise add PSST times cycle time.

PSHT = 0. Otherwise add PSHT times cycle time.

These synchronous timings define when the $\overline{\text{WAITA}}$ signals are detected in order to freeze (or relieve) the PCMCIA current cycle. The $\overline{\text{WAITA}}$ assertion will be effective only if it is detected 2 cycles before the PSL timer expiration. See Chapter 16, "PCMCIA Interface," in the *MPC885 PowerQUICC™ Family Reference Manual*.

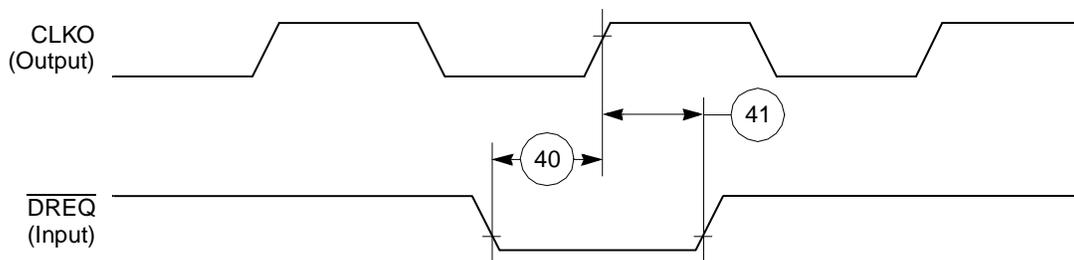


Figure 42. IDMA External Requests Timing Diagram

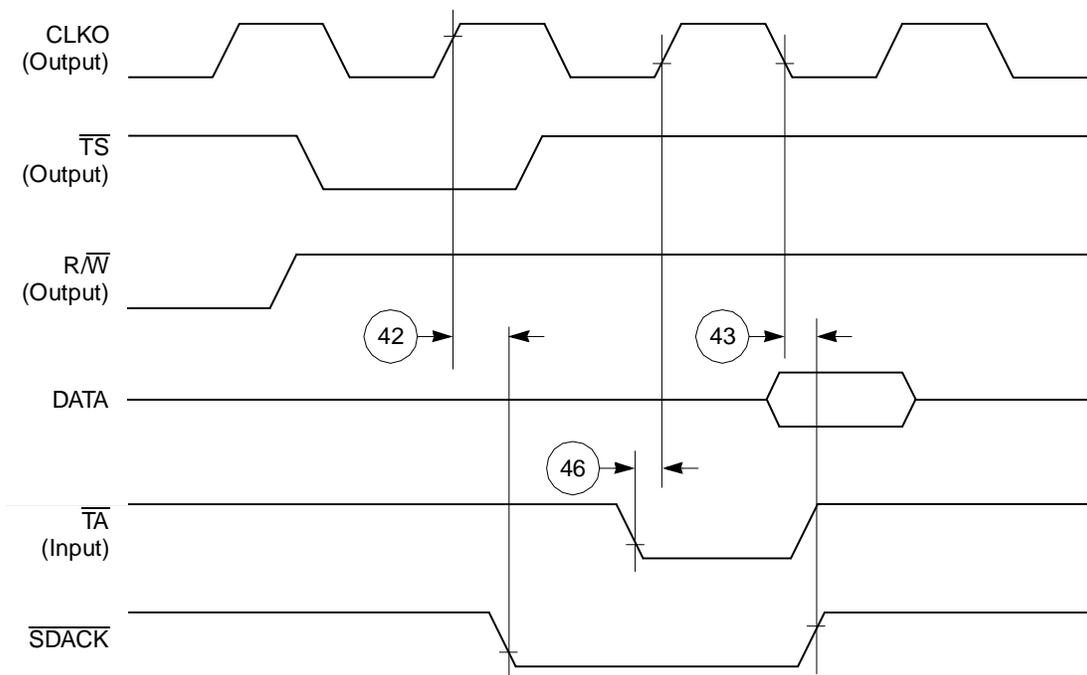


Figure 43. \overline{SDACK} Timing Diagram—Peripheral Write, Externally-Generated \overline{TA}

13.3 Baud Rate Generator AC Electrical Specifications

Table 19 provides the baud rate generator timings as shown in Figure 46.

Table 19. Baud Rate Generator Timing

Num	Characteristic	All Frequencies		Unit
		Min	Max	
50	BRGO rise and fall time	—	10	ns
51	BRGO duty cycle	40	60	%
52	BRGO cycle	40	—	ns

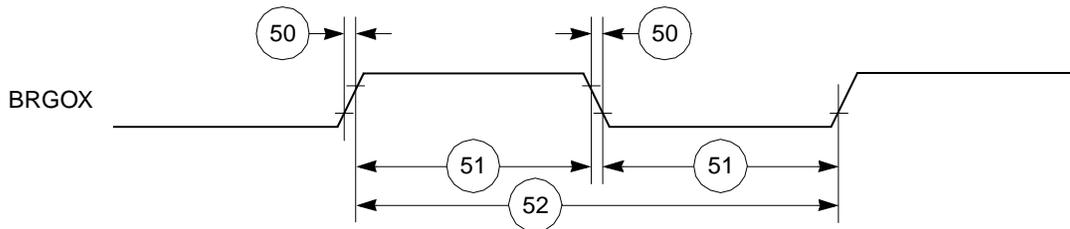


Figure 46. Baud Rate Generator Timing Diagram

13.4 Timer AC Electrical Specifications

Table 20 provides the general-purpose timer timings as shown in Figure 47.

Table 20. Timer Timing

Num	Characteristic	All Frequencies		Unit
		Min	Max	
61	TIN/ $\overline{\text{TGATE}}$ rise and fall time	10	—	ns
62	TIN/ $\overline{\text{TGATE}}$ low time	1	—	clk
63	TIN/ $\overline{\text{TGATE}}$ high time	2	—	clk
64	TIN/ $\overline{\text{TGATE}}$ cycle time	3	—	clk
65	CLKO low to $\overline{\text{TOUT}}$ valid	3	25	ns

13.6 SCC in NMSI Mode Electrical Specifications

Table 22 provides the NMSI external clock timing.

Table 22. NMSI External Clock Timing

Num	Characteristic	All Frequencies		Unit
		Min	Max	
100	RCLK3 and TCLK3 width high ¹	1/SYNCCLK	—	ns
101	RCLK3 and TCLK3 width low	1/SYNCCLK + 5	—	ns
102	RCLK3 and TCLK3 rise/fall time	—	15.00	ns
103	TXD3 active delay (from TCLK3 falling edge)	0.00	50.00	ns
104	$\overline{\text{RTS3}}$ active/inactive delay (from TCLK3 falling edge)	0.00	50.00	ns
105	$\overline{\text{CTS3}}$ setup time to TCLK3 rising edge	5.00	—	ns
106	RXD3 setup time to RCLK3 rising edge	5.00	—	ns
107	RXD3 hold time from RCLK3 rising edge ²	5.00	—	ns
108	$\overline{\text{CD3}}$ setup time to RCLK3 rising edge	5.00	—	ns

¹ The ratios SYNCCLK/RCLK3 and SYNCCLK/TCLK3 must be greater than or equal to 2.25/1.

² Also applies to $\overline{\text{CD}}$ and $\overline{\text{CTS}}$ hold time when they are used as external SYNC signals.

Table 23 provides the NMSI internal clock timing.

Table 23. NMSI Internal Clock Timing

Num	Characteristic	All Frequencies		Unit
		Min	Max	
100	RCLK3 and TCLK3 frequency ¹	0.00	SYNCCLK/3	MHz
102	RCLK3 and TCLK3 rise/fall time	—	—	ns
103	TXD3 active delay (from TCLK3 falling edge)	0.00	30.00	ns
104	$\overline{\text{RTS3}}$ active/inactive delay (from TCLK3 falling edge)	0.00	30.00	ns
105	$\overline{\text{CTS3}}$ setup time to TCLK3 rising edge	40.00	—	ns
106	RXD3 setup time to RCLK3 rising edge	40.00	—	ns
107	RXD3 hold time from RCLK3 rising edge ²	0.00	—	ns
108	$\overline{\text{CD3}}$ setup time to RCLK3 rising edge	40.00	—	ns

¹ The ratios SYNCCLK/RCLK3 and SYNCCLK/TCLK3 must be greater or equal to 3/1.

² Also applies to $\overline{\text{CD}}$ and $\overline{\text{CTS}}$ hold time when they are used as external SYNC signals.

Figure 53 through Figure 55 show the NMSI timings.

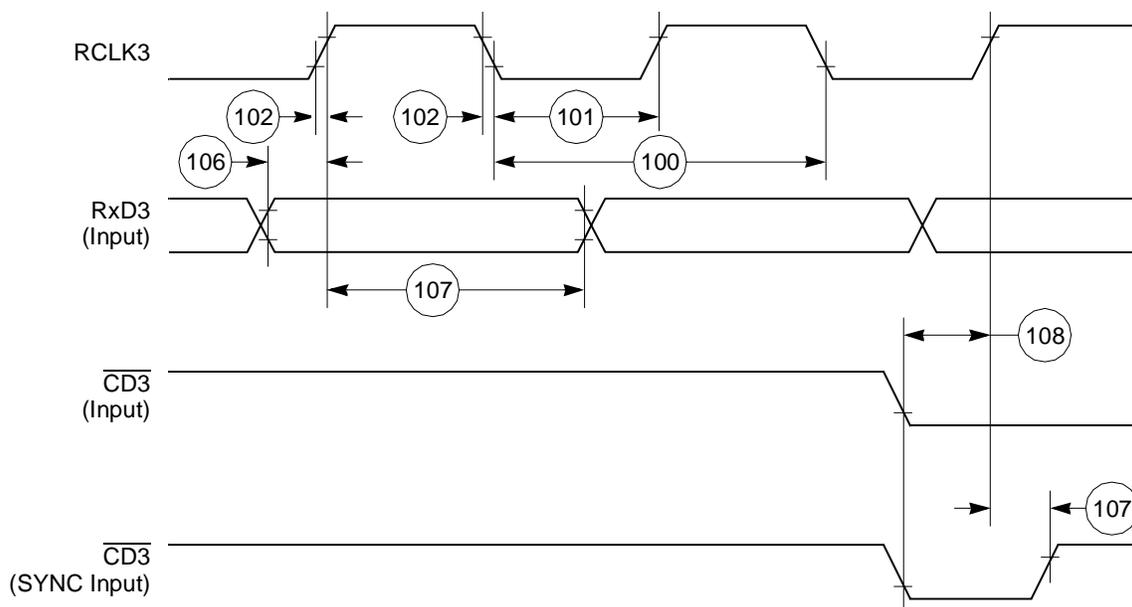


Figure 53. SCC NMSI Receive Timing Diagram

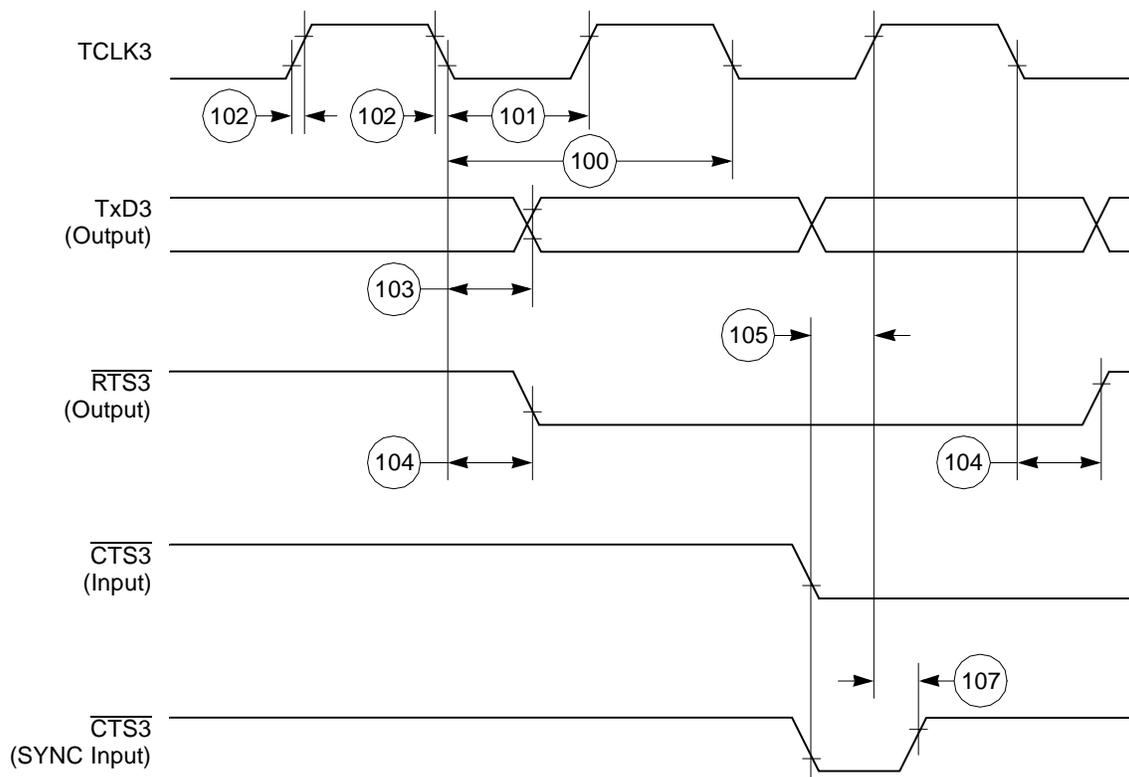


Figure 54. SCC NMSI Transmit Timing Diagram

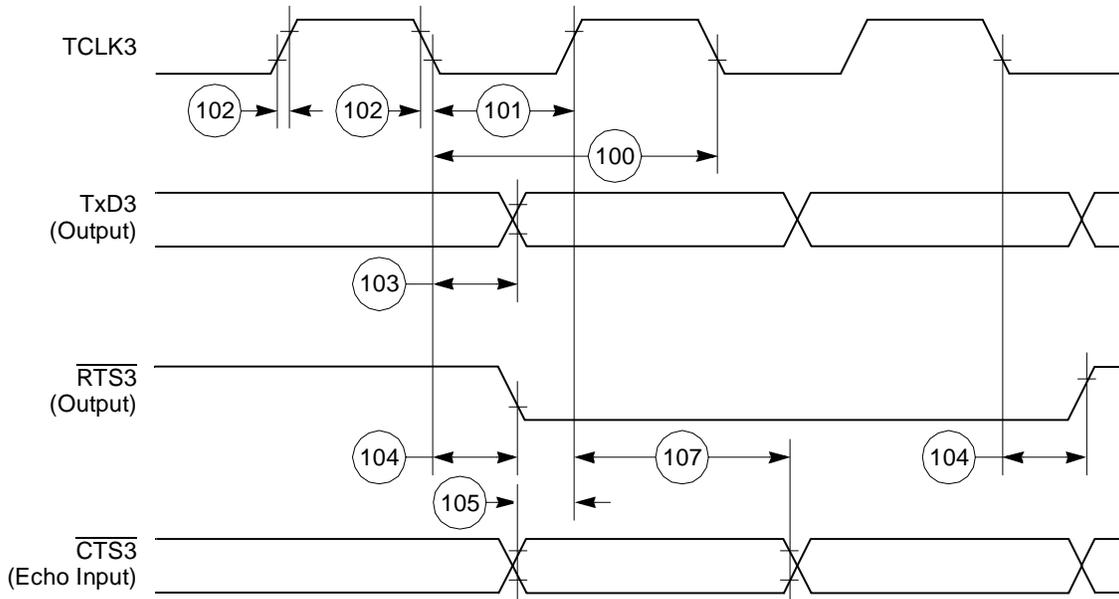


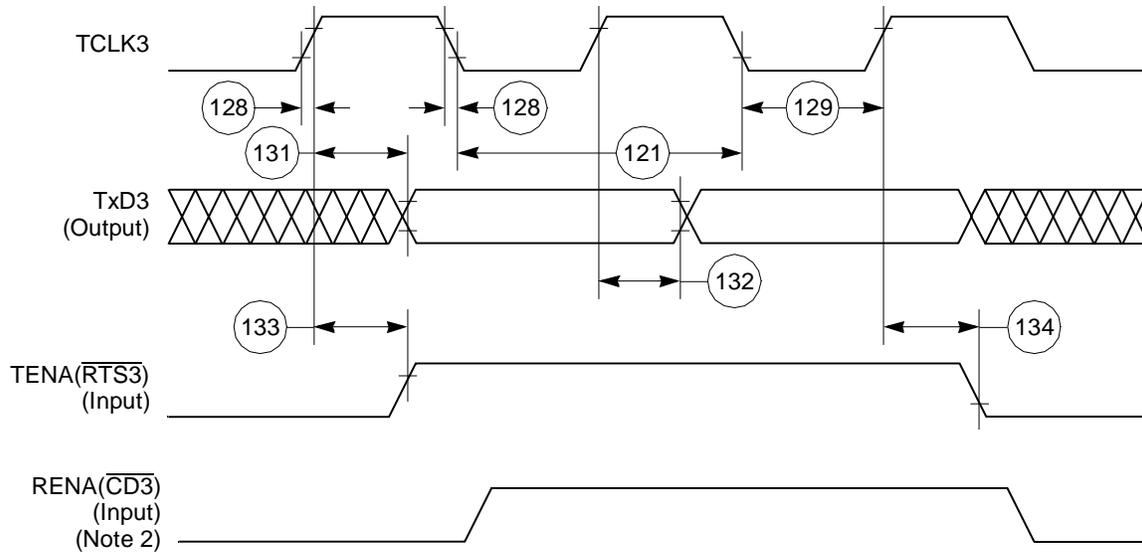
Figure 55. HDLC Bus Timing Diagram

13.7 Ethernet Electrical Specifications

Table 24 provides the Ethernet timings as shown in Figure 56 through Figure 58.

Table 24. Ethernet Timing

Num	Characteristic	All Frequencies		Unit
		Min	Max	
120	CLSN width high	40	—	ns
121	RCLK3 rise/fall time	—	15	ns
122	RCLK3 width low	40	—	ns
123	RCLK3 clock period ¹	80	120	ns
124	RXD3 setup time	20	—	ns
125	RXD3 hold time	5	—	ns
126	RENA active delay (from RCLK3 rising edge of the last data bit)	10	—	ns
127	RENA width low	100	—	ns
128	TCLK3 rise/fall time	—	15	ns
129	TCLK3 width low	40	—	ns
130	TCLK3 clock period ¹	99	101	ns
131	TXD3 active delay (from TCLK3 rising edge)	—	50	ns
132	TXD3 inactive delay (from TCLK3 rising edge)	6.5	50	ns
133	TENA active delay (from TCLK3 rising edge)	10	50	ns
134	TENA inactive delay (from TCLK3 rising edge)	10	50	ns



Notes:

1. Transmit clock invert (TCI) bit in GSMR is set.
2. If RENA is negated before TENA or RENA is not asserted at all during transmit, then the CSL bit is set in the buffer descriptor at the end of the frame transmission.

Figure 58. Ethernet Transmit Timing Diagram

13.8 SMC Transparent AC Electrical Specifications

Table 25 provides the SMC transparent timings as shown in Figure 59.

Table 25. SMC Transparent Timing

Num	Characteristic	All Frequencies		Unit
		Min	Max	
150	SMCLK clock period ¹	100	—	ns
151	SMCLK width low	50	—	ns
151A	SMCLK width high	50	—	ns
152	SMCLK rise/fall time	—	15	ns
153	SMTXD active delay (from SMCLK falling edge)	10	50	ns
154	SMRXD/SMSYNC setup time	20	—	ns
155	RXD1/SMSYNC hold time	5	—	ns

¹ SYNCCLK must be at least twice as fast as SMCLK.

Figure 66 shows the MII transmit signal timing diagram.

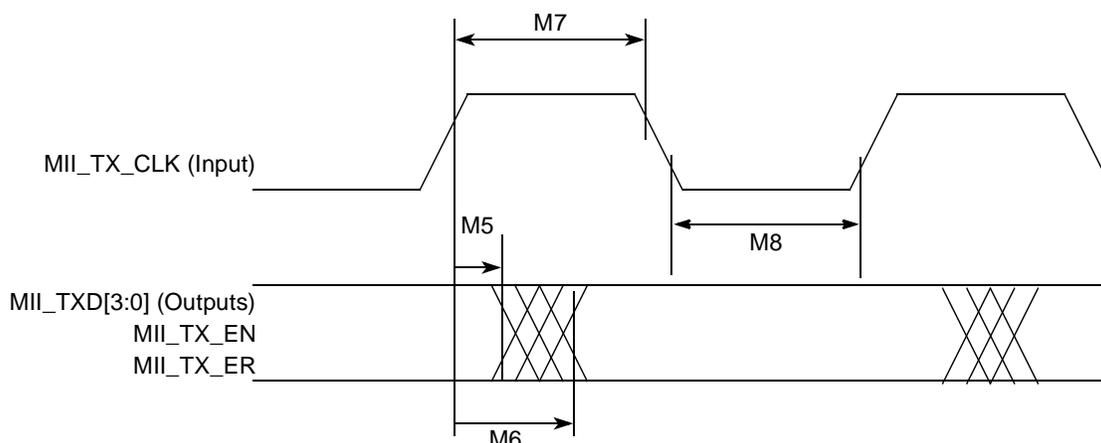


Figure 66. MII Transmit Signal Timing Diagram

15.3 MII Async Inputs Signal Timing (MII_CRIS, MII_COL)

Table 33 provides information on the MII async inputs signal timing.

Table 33. MII Async Inputs Signal Timing

Num	Characteristic	Min	Max	Unit
M9	MII_CRIS, MII_COL minimum pulse width	1.5	—	MII_TX_CLK period

Figure 67 shows the MII asynchronous inputs signal timing diagram.

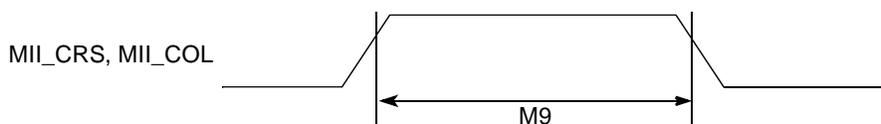


Figure 67. MII Async Inputs Timing Diagram

15.4 MII Serial Management Channel Timing (MII_MDIO, MII_MDC)

Table 34 provides information on the MII serial management channel signal timing. The FEC functions correctly with a maximum MDC frequency in excess of 2.5 MHz.

Table 34. MII Serial Management Channel Timing

Num	Characteristic	Min	Max	Unit
M10	MII_MDC falling edge to MII_MDIO output invalid (minimum propagation delay)	0	—	ns
M11	MII_MDC falling edge to MII_MDIO output valid (max prop delay)	—	25	ns
M12	MII_MDIO (input) to MII_MDC rising edge setup	10	—	ns
M13	MII_MDIO (input) to MII_MDC rising edge hold	0	—	ns
M14	MII_MDC pulse width high	40%	60%	MII_MDC period
M15	MII_MDC pulse width low	40%	60%	MII_MDC period

Table 36 contains a list of the MPC875/MPC870 input and output signals and shows multiplexing and pin assignments.

Table 36. Pin Assignments—JEDEC Standard

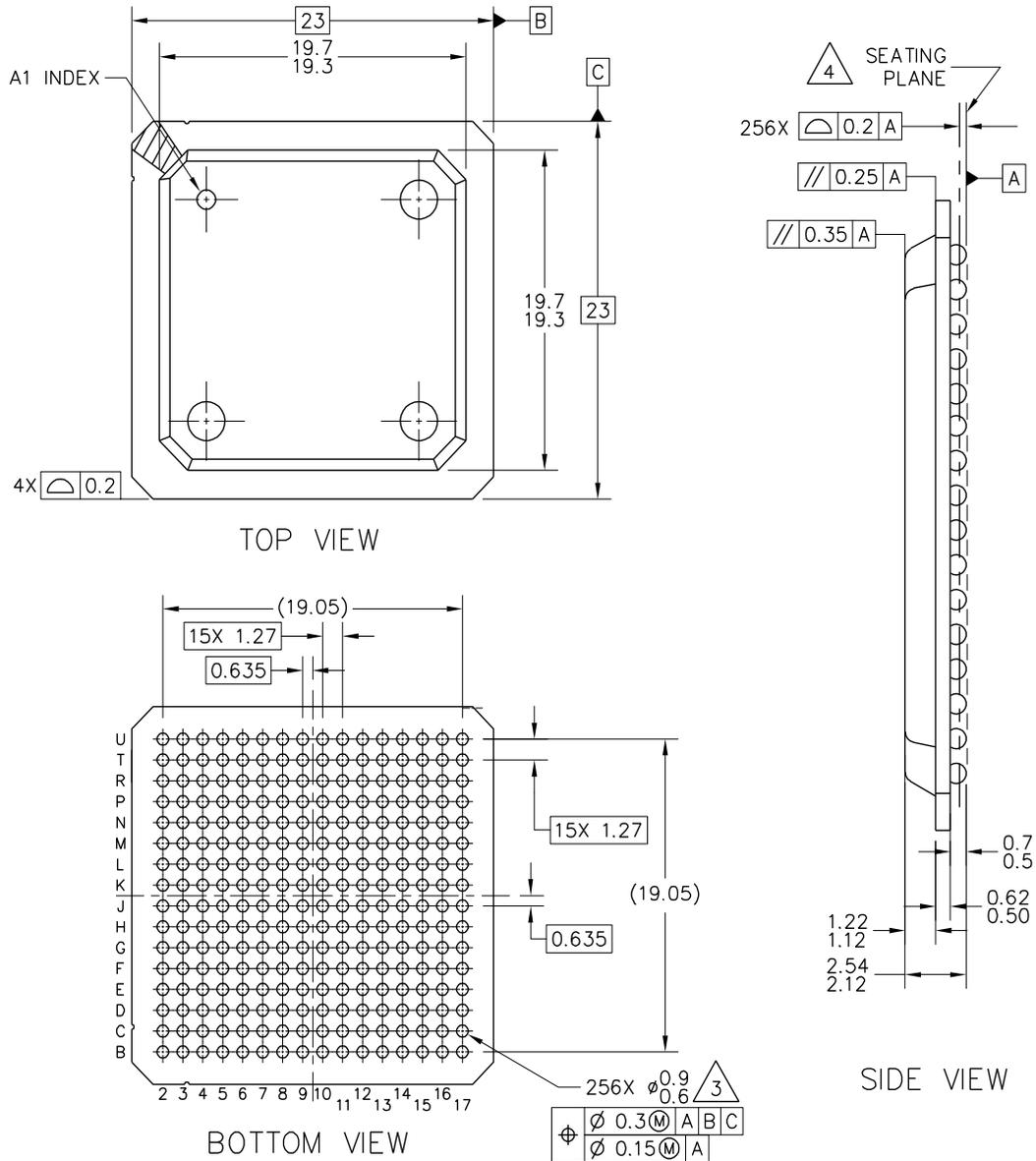
Name	Pin Number	Type
A[0:31]	R16, N14, M14, P15, P17, P16, N15, N16, M15, N17, L14, M16, L15, M17, K14, L16, L17, K17, G17, K15, J16, J15, G16, J14, H17, H16, G15, K16, H14, J17, H15, F17	Bidirectional Three-state (3.3 V only)
TSIZ0, $\overline{\text{REG}}$	F16	Bidirectional Three-state (3.3 V only)
TSIZ1	G14	Bidirectional Three-state (3.3 V only)
$\text{RD}/\overline{\text{WR}}$	D13	Bidirectional Three-state (3.3 V only)
$\overline{\text{BURST}}$	B9	Bidirectional Three-state (3.3 V only)
$\overline{\text{BDIP}}$, $\overline{\text{GPL_B5}}$	C13	Output
$\overline{\text{TS}}$	C11	Bidirectional Active pull-up (3.3 V only)
$\overline{\text{TA}}$	C12	Bidirectional Active pull-up (3.3 V only)
$\overline{\text{TEA}}$	B12	Open-drain
$\overline{\text{BI}}$	B13	Bidirectional Active pull-up (3.3 V only)
$\overline{\text{IRQ2}}$, $\overline{\text{RSV}}$	C9	Bidirectional Three-state (3.3 V only)
$\overline{\text{IRQ4}}$, $\overline{\text{KR}}$, $\overline{\text{RETRY}}$, SPKROUT	E9	Bidirectional Three-state (3.3 V only)
D[0:31]	L5, N3, L3, L2, R2, K2, H3, G2, R3, M3, N2, M2, M4, N4, K5, K3, K4, P3, J2, J3, J4, J5, H2, P2, H4, H5, G5, L4, G3, F2, F3, E2	Bidirectional Three-state (3.3 V only)
CR, $\overline{\text{IRQ3}}$	E10	Input
FRZ, $\overline{\text{IRQ6}}$	B10	Bidirectional Three-state (3.3 V only)
$\overline{\text{BR}}$	B11	Bidirectional (3.3 V only)
$\overline{\text{BG}}$	D10	Bidirectional (3.3 V only)
$\overline{\text{BB}}$	C10	Bidirectional Active pull-up (3.3 V only)
$\overline{\text{IRQ0}}$	M6	Input (3.3 V only)
$\overline{\text{IRQ1}}$	P5	Input (3.3 V only)
$\overline{\text{IRQ7}}$	N5	Input (3.3 V only)
$\overline{\text{CS}}$ [0:5]	B14, E11, C14, B15, E13, B16	Output

Table 36. Pin Assignments—JEDEC Standard (continued)

Name	Pin Number	Type
IP_A6	F4	Input (3.3 V only)
IP_A7	C2	Input (3.3 V only)
ALE_B, DSCK	C8	Bidirectional Three-state (3.3 V only)
IP_B[0:1], IWP[0:1], VFLS[0:1]	B8, D9	Bidirectional (3.3 V only)
OP0	B6	Bidirectional (3.3 V only)
OP1	C6	Output
OP2, MODCK1, \overline{STS}	B5	Bidirectional (3.3 V only)
OP3, MODCK2, DSDO	B2	Bidirectional (3.3 V only)
BADDR[28:29]	E8, C5	Output
BADDR30, \overline{REG}	D8	Output
\overline{AS}	C7	Input (3.3 V only)
PA15, USBRXD	P14	Bidirectional
PA14, USBOE	U16	Bidirectional (Optional: open-drain)
PA11, RXD4, MII1-TXD0, RMII1-TXD0	R9	Bidirectional (Optional: open-drain) (5-V tolerant)
PA10, MII1-TXERR, TIN4, CLK7	R12	Bidirectional (Optional: open-drain) (5-V tolerant)
PA7, CLK1, BRGO1, TIN1	R11	Bidirectional
PA6, CLK2, $\overline{TOUT1}$	P11	Bidirectional
PA4, $\overline{CTS4}$, MII1-TXD1, RMII1-TXD1	P7	Bidirectional
PA3, MII1-RXER, RMII1-RXER, BRGO3	R5	Bidirectional (5-V tolerant)
PA2, MII1-RXDV, RMII1-CRS_DV, TXD4	N6	Bidirectional (5-V tolerant)
PA1, MII1-RXD0, RMII1-RXD0, BRGO4	T4	Bidirectional (5-V tolerant)
PA0, MII1-RXD1, RMII1-RXD1, TOUT4	P6	Bidirectional (5-V tolerant)
PB31, \overline{SPISEL} , MII1-TXCLK, RMII1-REFCLK	T5	Bidirectional (Optional: open-drain) (5-V tolerant)

16.2 Mechanical Dimensions of the PBGA Package

Figure 70 shows the mechanical dimensions of the PBGA package.



NOTES:

1. ALL DIMENSIONS ARE IN MILLIMETERS.
2. INTERPRET DIMENSIONS AND TOLERANCES PER ASME Y14.5M—1994.
3. MAXIMUM SOLDER BALL DIAMETER MEASURED PARALLEL TO DATUM A.
4. DATUM A, THE SEATING PLANE, IS DEFINED BY THE SPHERICAL CROWNS OF THE SOLDER BALLS.

Note: Solder sphere composition is 95.5%Sn 45%Ag 0.5%Cu for MPC875/MPC870VRXXX.

Solder sphere composition is 62%Sn 36%Pb 2%Ag for MPC875/MPC870ZTXXX.

Figure 70. Mechanical Dimensions and Bottom Surface Nomenclature of the PBGA Package

17 Document Revision History

Table 37 lists significant changes between revisions of this hardware specification.

Table 37. Document Revision History

Revision Number	Date	Changes
0	2/2003	Initial release.
0.1	3/2003	Took out the time-slot assigner and changed the SCC for SCC3 to SCC4.
0.2	5/2003	Changed the package drawing, removed all references to Data Parity. Changed the SPI Master Timing Specs. 162 and 164. Added the RMI and USB timing. Added the 80-MHz timing.
0.3	5/2003	Made sure the pin types were correct. Changed the Features list to agree with the MPC885.
0.4	5/2003	Corrected the signals that had overlines on them. Made corrections on two pins that were typos.
0.5	5/2003	Changed the pin descriptions for PD8 and PD9.
0.6	5/2003	Changed a few typos. Put back the I ² C. Put in the new reset configuration, corrected the USB timing.
0.7	6/2003	Changed the pin descriptions per the June 22 spec, removed Utopia from the pin descriptions, changed PADIR, PBDIR, PCDIR and PDDIR to be 0 in the Mandatory Reset Config.
0.8	8/2003	Added the reference to USB 2.0 to the Features list and removed 1.1 from USB on the block diagrams.
0.9	8/2003	Changed the USB description to full-/low-speed compatible.
1.0	9/2003	Added the DSP information in the Features list. Put a new sentence under Mechanical Dimensions. Fixed table formatting. Nontechnical edits. Released to the external web.
1.1	10/2003	Added TDmB to the MPC875 Features list, the MPC875 Block Diagram, added 13.5 Serial Interface AC Electrical Specifications, and removed TDmA from the pin descriptions.
2.0	12/2003	Changed DBGc in the Mandatory Reset Configuration to X1. Changed the maximum operating frequency to 133 MHz. Put the timing in the 80 MHz column. Put in the orderable part numbers. Rounded the timings to hundredths in the 80 MHz column. Put the pin numbers in footnotes by the maximum currents in Table 6. Changed 22 and 41 in the Timing. Put TBD in the Thermal table.

THIS PAGE INTENTIONALLY LEFT BLANK

How to Reach Us:

Home Page:

www.freescale.com

Web Support:

<http://www.freescale.com/support>

USA/Europe or Locations Not Listed:

Freescale Semiconductor, Inc.
 Technical Information Center, EL516
 2100 East Elliot Road
 Tempe, Arizona 85284
 +1-800-521-6274 or
 +1-480-768-2130
www.freescale.com/support

Europe, Middle East, and Africa:

Freescale Halbleiter Deutschland GmbH
 Technical Information Center
 Schatzbogen 7
 81829 Muenchen, Germany
 +44 1296 380 456 (English)
 +46 8 52200080 (English)
 +49 89 92103 559 (German)
 +33 1 69 35 48 48 (French)
www.freescale.com/support

Japan:

Freescale Semiconductor Japan Ltd.
 Headquarters
 ARCO Tower 15F
 1-8-1, Shimo-Meguro, Meguro-ku
 Tokyo 153-0064
 Japan
 0120 191014 or
 +81 3 5437 9125
support.japan@freescale.com

Asia/Pacific:

Freescale Semiconductor Hong Kong Ltd.
 Technical Information Center
 2 Dai King Street
 Tai Po Industrial Estate
 Tai Po, N.T., Hong Kong
 +800 2666 8080
support.asia@freescale.com

For Literature Requests Only:

Freescale Semiconductor
 Literature Distribution Center
 P.O. Box 5405
 Denver, Colorado 80217
 +1-800 441-2447 or
 +1-303-675-2140
 Fax: +1-303-675-2150
LDCForFreescaleSemiconductor@hibbertgroup.com

Information in this document is provided solely to enable system and software implementers to use Freescale Semiconductor products. There are no express or implied copyright licenses granted hereunder to design or fabricate any integrated circuits or integrated circuits based on the information in this document.

Freescale Semiconductor reserves the right to make changes without further notice to any products herein. Freescale Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does Freescale Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation consequential or incidental damages. "Typical" parameters which may be provided in Freescale Semiconductor data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. Freescale Semiconductor does not convey any license under its patent rights nor the rights of others. Freescale Semiconductor products are not designed, intended, or authorized for use as components in systems intended for surgical implant into the body, or other applications intended to support or sustain life, or for any other application in which the failure of the Freescale Semiconductor product could create a situation where personal injury or death may occur. Should Buyer purchase or use Freescale Semiconductor products for any such unintended or unauthorized application, Buyer shall indemnify and hold Freescale Semiconductor and its officers, employees, subsidiaries, affiliates, and distributors harmless against all claims, costs, damages, and expenses, and reasonable attorney fees arising out of, directly or indirectly, any claim of personal injury or death associated with such unintended or unauthorized use, even if such claim alleges that Freescale Semiconductor was negligent regarding the design or manufacture of the part.

Freescale™ and the Freescale logo are trademarks of Freescale Semiconductor, Inc. The Power Architecture and Power.org word marks and the Power and Power.org logos and related marks are trademarks and service marks licensed by Power.org. IEEE 802.3, 802.11i, and 1149.1 are trademarks or registered trademarks of the Institute of Electrical and Electronics Engineers, Inc. (IEEE). This product is not endorsed or approved by the IEEE. All other product or service names are the property of their respective owners.

© Freescale Semiconductor, Inc., 2003–2007. All rights reserved.

